

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: COPPOLA, Giuseppe; FERRARO, Pietro; IODICE, Mario; DE NICOLA, Sergio

SERIAL NO.:

FILED: Herewith

TITLE: INTERFEROMETRIC SYSTEM FOR THE SIMULTANEOUS MEASUREMENT OF THE INDEX OF REFRACTION AND OF THE THICKNESS OF TRANSPARENT MATERIALS, AND RELATED PROCEDURE

REMARKS ON PRELIMINARY AMENDMENT

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In this preliminary amendment, please consider the following remarks in conjunction with the amendments to the above-identified application as follows:

REMARKS

The present Preliminary Amendment has been entered for the purpose of placing the application into a more proper U.S. format. In particular, certain grammatical and idiomatic inconsistencies have been corrected by amendment to the specification, and the application is corrected for certain typographical errors found in the originally submitted application. No new matter has been added by these amendments. The present application is an English translation of an originally Italian priority document.

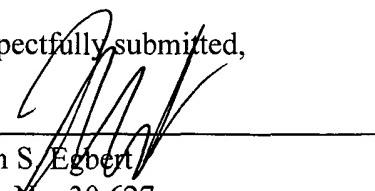
The Claims and Abstract have been amended so as to conform with U.S. requirements. The claims were also amended to cancel multiple dependent claims.

Applicant respectfully requests that the present Amendment be entered prior to an initial Official Action on the present application.

Respectfully submitted,

7-22-03

Date

  
John S. Egbert  
Reg. No. 30,627  
Andrew W. Chu  
Reg. No. 46,625  
Attorney for Applicant  
Harrison & Egbert  
412 Main Street, 7<sup>th</sup> Floor  
Houston, Texas 77002  
(713)224-8080  
(713)223-4873 fax